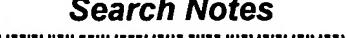


Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/786,388	STRECK ET AL.
	Examiner Binh X. Tran	Art Unit 1765

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner